

TF11N70-VB Datasheet N-Channel 700V (D-S) Super Junction Power MOSFET

PRODUCT SUMMARY				
V _{DS} (V) at T _J max.	700			
R _{DS(on)} at 25 °C (Ω)	V _{GS} = 10 V 0.7			
Q _g max. (nC)	23			
Q _{gs} (nC)	2.3			
Q _{gd} (nC)	15			
Configuration	Single			

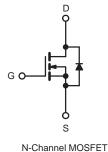
FEATURES

- Low figure-of-merit (FOM) Ron x Qa
- Low input capacitance (Ciss)
- · Reduced switching and conduction losses
- Ultra low gate charge (Q_a)
- Avalanche energy rated (UIS)

APPLICATIONS

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- Lighting
 - High-intensity discharge (HID)
 - Fluorescent ballast lighting
- Industrial





ABSOLUTE MAXIMUM RATINGS (T_C = 25 °C, unless otherwise noted) SYMBOL **PARAMETER** LIMIT UNIT Drain-Source Voltage 700 V_{DS} ± 30 Gate-Source Voltage V_{GS} $T_C = 25$ °C 7 Continuous Drain Current (T_{.I} = 150 °C) V_{GS} at 10 V I_D T_C = 100 °C Α 5.9 Pulsed Drain Current a I_{DM} 12 Linear Derating Factor 1.89/1.55/0.5 W/°C Single Pulse Avalanche Energy b E_{AS} mJ 87 Maximum Power Dissipation P_D 99/97/46 W Operating Junction and Storage Temperature Range -55 to +150 °C T_J, T_{stq} Drain-Source Voltage Slope T_J = 125 °C 50 dV/dt V/ns Reverse Diode dV/dt d 3.2 °С Soldering Recommendations (Peak Temperature) c for 10 s 300

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature.
- b. V_{DD} = 50 V, starting T_J = 25 °C, L = 28.2 mH, R_g = 25 Ω , I_{AS} = 3.5 A.
- c. 1.6 mm from case.
- d. $I_{SD} \le I_D$, $dI/dt = 100 \text{ A/}\mu\text{s}$, starting $T_J = 25 \,^{\circ}\text{C}$.



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	72	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	0.7	- C/VV	

PARAMETER	SYMBOL	TES	TEST CONDITIONS		TYP.	MAX.	UNIT
Static				•	•		
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} =	= 0 V, I _D = 250 μA	700	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I _D = 1 mA	-	0.65	-	V/°C
Gate-Source Threshold Voltage (N)	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D = 250 μA	2	-	4	V
	I _{GSS}	V _{GS} = ± 20 V		-	-	± 100	nA
Gate-Source Leakage			V _{GS} = ± 30 V		-	± 1	μA
		V _{DS} = 700 V, V _{GS} = 0 V		-	-	1	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 700 \text{ V}, V_{GS} = 0 \text{ V}$ $V_{DS} = 520 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 125 \text{ °C}$		-	-	10	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 4 A	-	0.75	-	Ω
Forward Transconductance	9 _{fs}		= 30 V, I _D = 4 A	-	17	-	S
Dynamic							
Input Capacitance	C _{iss}	V _{GS} = 0 V,		-	366	-	T
Output Capacitance	C _{oss}	1	$V_{DS} = 100 \text{ V},$	-	27	-	1 1
Reverse Transfer Capacitance	C _{rss}	7	f = 1 MHz		13	-	pF
Effective Output Capacitance, Energy Related ^a	C _{o(er)}			-	46	-	
Effective Output Capacitance, Time Related ^b	C _{o(tr)}	$V_{DS} = 0.0$	to 520 V, V _{GS} = 0 V	-	64	-	
Total Gate Charge	Qg			-	26		
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V	$I_D = 4 A, V_{DS} = 520 V$	-	2.1	-	nC
Gate-Drain Charge	Q _{gd}	1		-	2.8	-	1
Turn-On Delay Time	t _{d(on)}			-	26	-	
Rise Time	t _r	Von	= 520 V I _D = 4 A	-	55.7	-]
Turn-Off Delay Time	t _{d(off)}			-	ns		
Fall Time	t _f			-	41	-	1
Gate Input Resistance	R _g	f = 1	MHz, open drain	-	3.5	-	Ω
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	7	
Pulsed Diode Forward Current	I _{SM}			-	-	18	- A
Diode Forward Voltage	V _{SD}	T _J = 25 °C, I _S = 4 A, V _{GS} = 0 V		-	-	1.4	V
Reverse Recovery Time	t _{rr}			-	192	-	ns
Reverse Recovery Charge	Q _{rr}	T ₁ = 25 °C ₁ ₂ = 1 ₀ = 4 A		-	μC		
Reverse Recovery Current	I _{RRM}		100 AγμS, VR = 400 V	_	11	_	A

Notes

- a. $C_{oss(er)}$ is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} . b. $C_{oss(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DSS} .



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

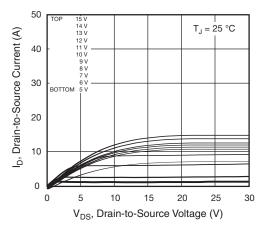


Fig. 1 - Typical Output Characteristics

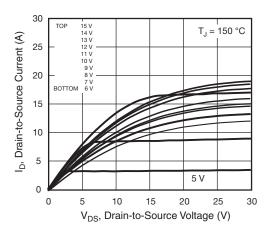


Fig. 2 - Typical Output Characteristics

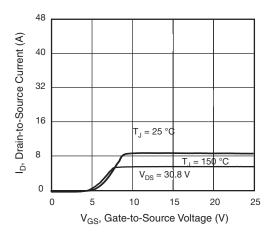


Fig. 3 - Typical Transfer Characteristics

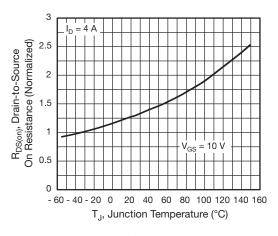


Fig. 4 - Normalized On-Resistance vs. Temperature

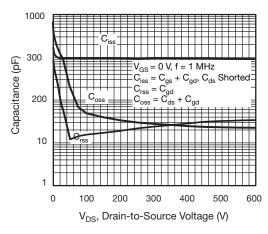


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

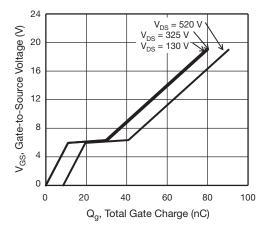


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



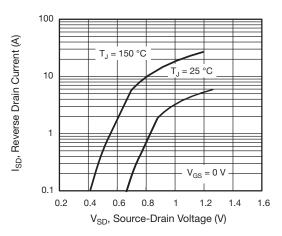
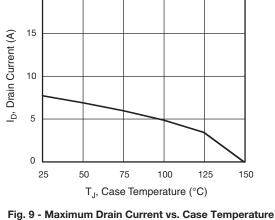


Fig. 7 - Typical Source-Drain Diode Forward Voltage



20

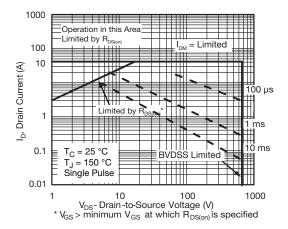


Fig. 8 - Maximum Safe Operating Area

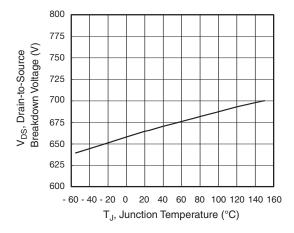


Fig. 10 - Temperature vs. Drain-to-Source Voltage

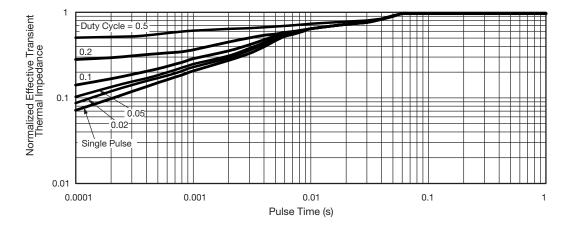


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case



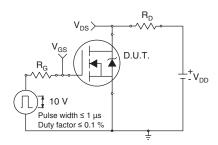


Fig. 12 - Switching Time Test Circuit

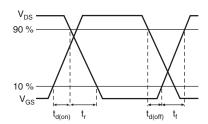


Fig. 13 - Switching Time Waveforms

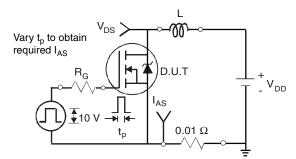


Fig. 14 - Unclamped Inductive Test Circuit

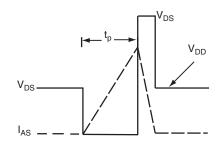


Fig. 15 - Unclamped Inductive Waveforms

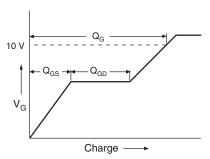


Fig. 16 - Basic Gate Charge Waveform

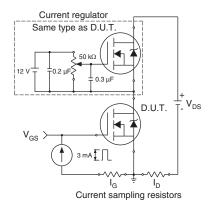
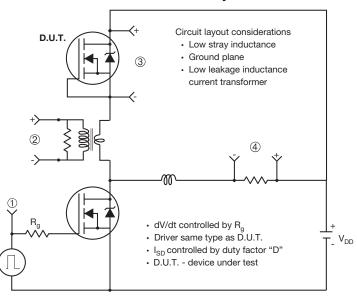


Fig. 17 - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



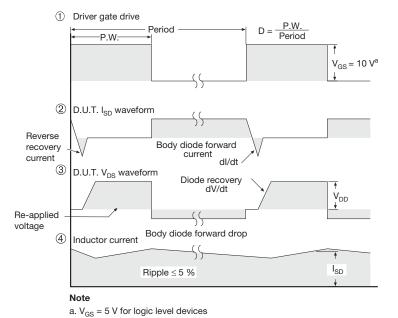
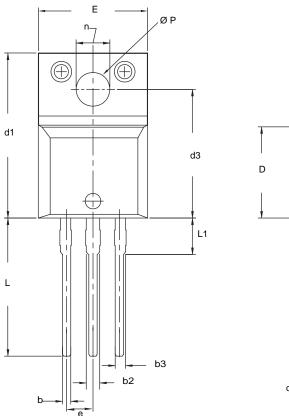
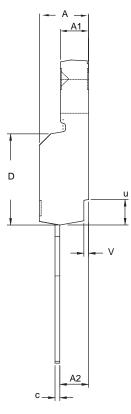


Fig. 18 - For N-Channel



TO-220 FULLPAK (HIGH VOLTAGE)





DIM.	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
А	4.570	4.830	0.180	0.190
A1	2.570	2.830	0.101	0.111
A2	2.510	2.850	0.099	0.112
b	0.622	0.890	0.024	0.035
b2	1.229	1.400	0.048	0.055
b3	1.229	1.400	0.048	0.055
С	0.440	0.629	0.017	0.025
D	8.650	9.800	0.341	0.386
d1	15.88	16.120	0.622	0.635
d3	12.300	12.920	0.484	0.509
E	10.360	10.630	0.408	0.419
е	2.54 BSC		0.100 BSC	
L	13.200	13.730	0.520	0.541
L1	3.100	3.500	0.122	0.138
n	6.050	6.150	0.238	0.242
ØΡ	3.050	3.450	0.120	0.136
u	2.400	2.500	0.094	0.098
V	0.400	0.500	0.016	0.020

ECN: X09-0126-Rev. B, 26-Oct-09 DWG: 5972

Notes

- To be used only for process drawing.
 These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads.
 All critical dimensions should C meet C_{pk} > 1.33.
 All dimensions include burrs and plating thickness.
 No chipping or package damage.



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